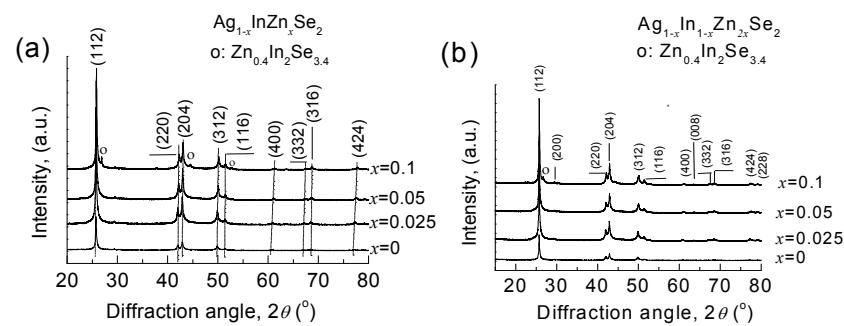
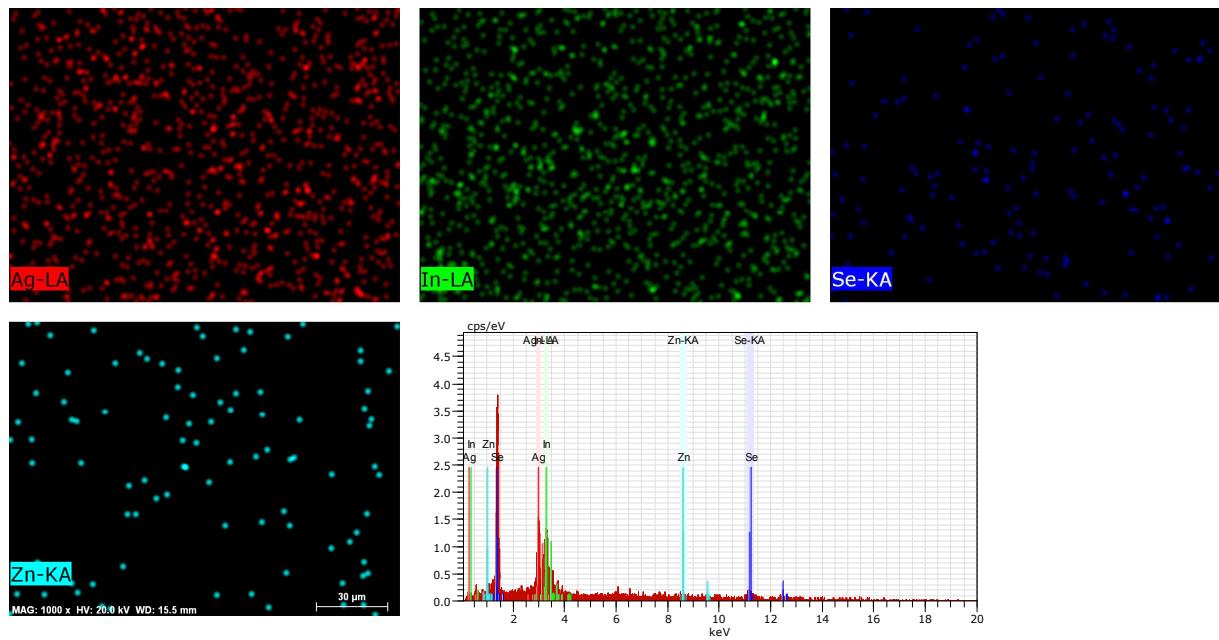


Supplementary Figure 1 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



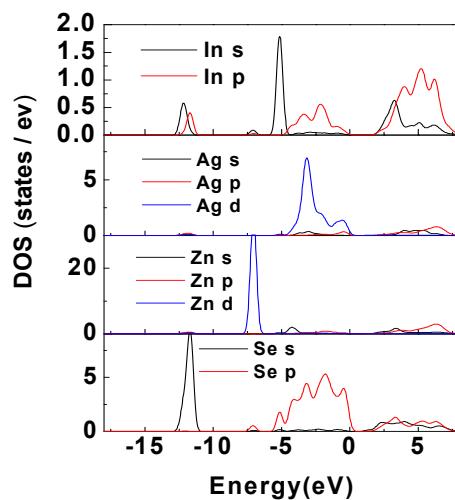
Supplementary Figure 1 X-ray diffraction patterns of the powders (a) $\text{Ag}_{1-x}\text{InZn}_x\text{Se}_2$, and (b) $\text{Ag}_{1-x}\text{In}_{1-x}\text{Zn}_{2x}\text{Se}_2$.

Supplementary Figure 2 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



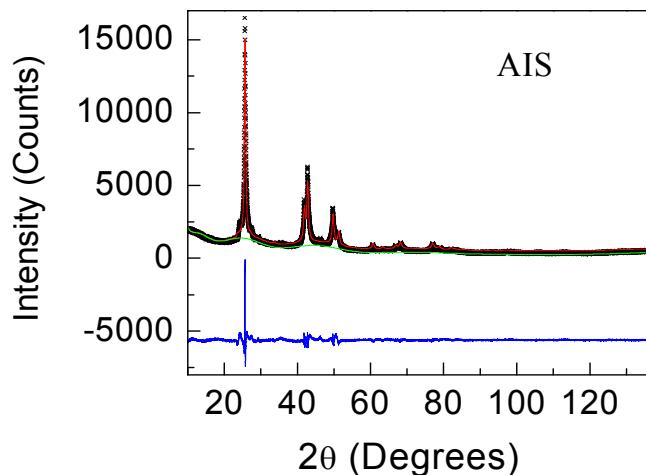
Supplementary Figure 2 A mapping of EPMA and energy dispersive x-ray spectra of $\text{Ag}_{1-x}\text{In}_{1-x}\text{Zn}_{2x}\text{Se}_2$ ($x=0.1$).

Supplementary Figure 3 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



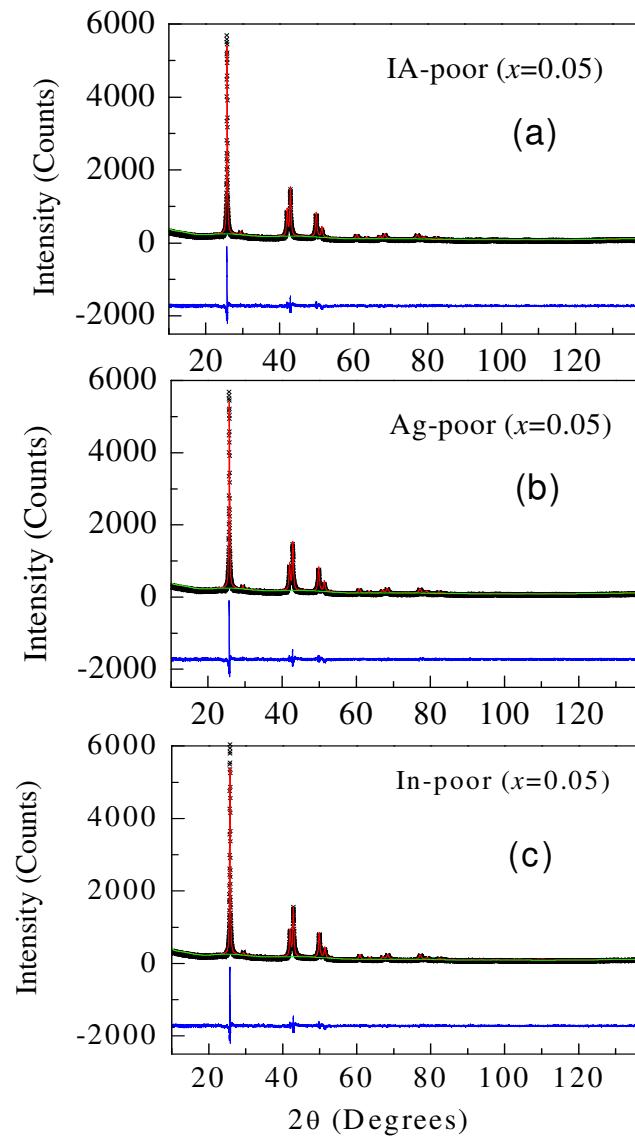
Supplementary Figure 3 Partial density of States (DOS) of different elements in Zn substituted AgInSe₂.

Supplementary Figure 4 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



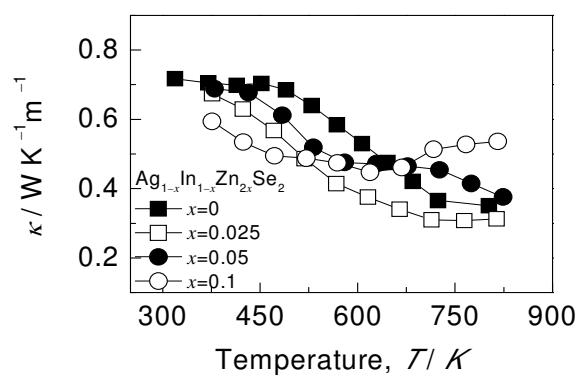
Supplementary Figure 4 Rietveld refinement using X-ray diffraction ($w_{Rp}=0.0732$ and $R_p=0.0556$) data for AgInSe₂. The goodness of fit $\chi^2=1.612$. Observed (×××) and calculated (solid line) X-ray powder diffraction patterns are shown.

Supplementary Figure 5 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



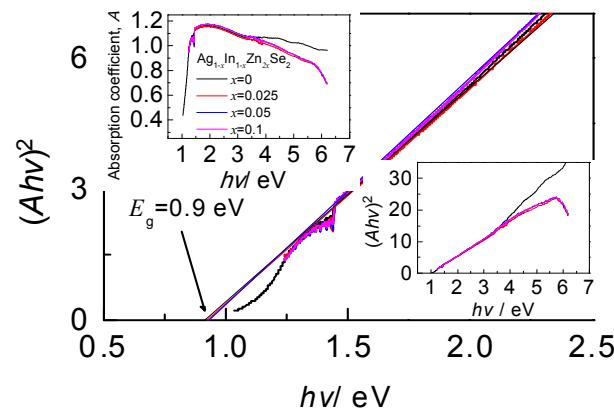
Supplementary Figure 5 Rietveld refinement using X-ray diffraction data for (a) IA-poor, (b) Ag-poor and (c) In-poor with $x = 0.05$. Observed ($\times \times \times$) and calculated (solid line) X-ray powder diffraction patterns are shown.

Supplementary Figure 6 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



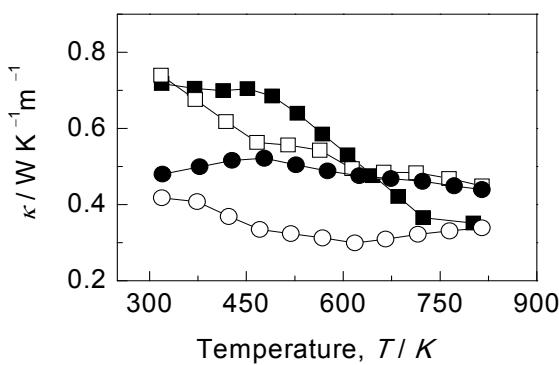
Supplementary Figure 6 Thermal conductivities (κ) of $\text{Ag}_{1-x}\text{In}_{1-x}\text{Zn}_{2x}\text{Se}_2$ as a function of the temperature.

Supplementary Figure 7 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



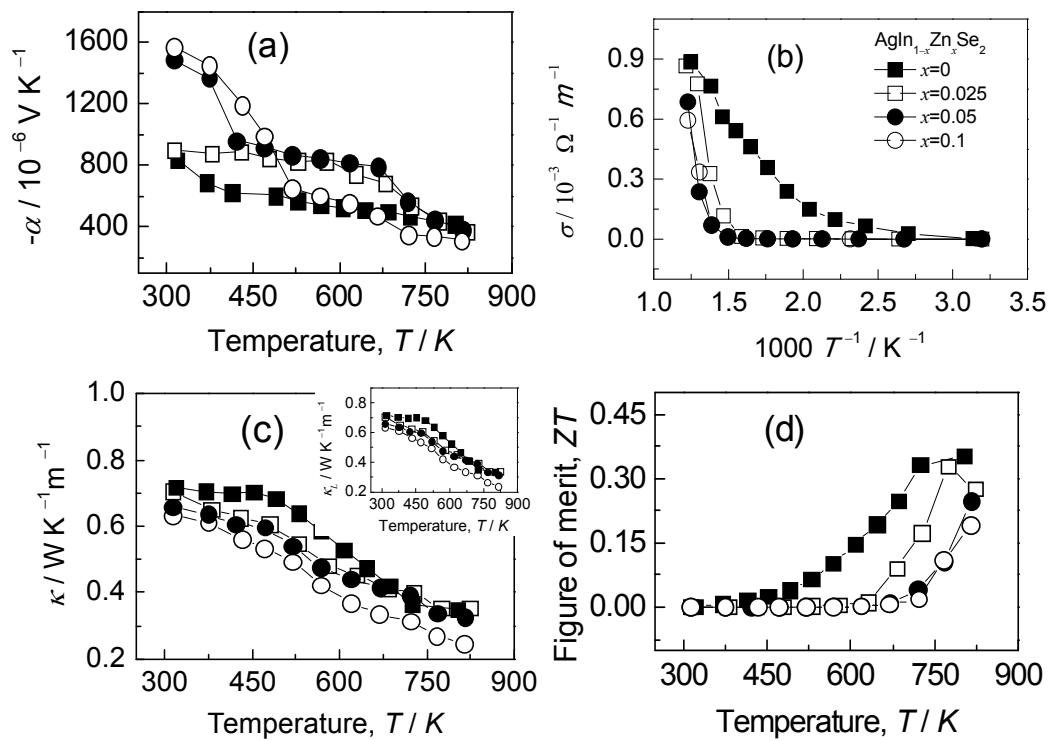
Supplementary Figure 7. Experimentally determined bandgap E_g of $\text{Ag}_{1-x}\text{In}_{1-x}\text{Zn}_{2x}\text{Se}_2$. An upper left insert is the absorption coefficient spectra A ($h\nu$), A is the absorption coefficient, $h\nu$ is the photon energy, and low right insert is the full relations of $(A(h\nu))^2 = (h\nu - E_g)$.

Supplementary Figure 8 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



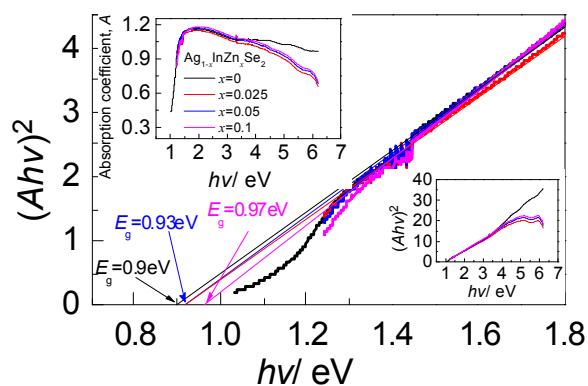
Supplementary Figure 8 Thermal conductivities (κ) of $\text{Ag}_{1-x}\text{InZn}_x\text{Se}_2$ as a function of the temperature.

Supplementary Figure 9 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



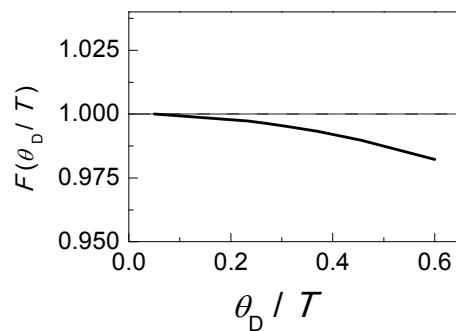
Supplementary Figure 9 Thermoelectric properties of $\text{AgIn}_{1-x}\text{Zn}_x\text{Se}_2$, (a) Seebeck coefficients (α), (b) electrical conductivities (σ), (c) Thermal conductivities (κ), an insert is the relation of κ_L-T , (d) ZT values.

Supplementary Figure 10 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



Supplementary Figure 10 Experimentally determined bandgap E_g of $\text{Ag}_{1-x}\text{InZn}_x\text{Se}_2$. An upper left insert is the absorption coefficient spectra A ($h\nu$), and low right insert is the full relations of $(A h \nu)^2 = (h \nu - E_g)$.

Supplementary Figure 11 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)



Supplementary Figure 11 Debye function $F(\theta_D/T)$ as a function of θ_D/T used in the estimation of the heat capacities (C_p) of AgInSe_2 based semiconductors.

Supplementary Table 1 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)

Supplementary Table 1 The chemical compositions (relative molars) identified using EPMA for $\text{Ag}_{1-x}\text{InZn}_x\text{Se}_2$, $\text{Ag}_{1-x}\text{In}_{1-x}\text{Zn}_{2x}\text{Se}_2$ ($x=0, 0.1$) (taken from a mapping)

Sample	x	Ag	In	Zn	Se
AIS		1.02	1.04		1.94
IA-AIS	0.10	0.91	0.94	0.19	1.96
Ag-AIS	0.10	0.92	1.02	0.09	1.97

Supplementary Table 2 submitted by the authors (Li Wang, Pengzhan Ying, Yuan Deng, Hong Zhou, Zhengliang Du, Jiaolin Cui)

Supplementary Table 2 Structural Parameters for AgInSe₂ Obtained by Rietveld Refinements

atom	Wyc	x	y	z	SOF	100Uiso [Å ²]
Ag	4 <i>a</i>	0	0	0	0.9522 (2)	2.2020 (5)
In	4 <i>b</i>	0	0	0.5	0.9956 (3)	2.3820 (5)
Se	8 <i>d</i>	0.2341(3)	0.25	0.125	0.9720 (4)	1.5840 (4)

Supplementary Table 3 Structural parameters and refinement details for IA–poor compounds ($\text{Ag}_{1-x}\text{In}_{1-x}\text{Zn}_{2x}\text{Se}_2$) obtained by Rietveld refinements

Parameters	$x = 0.025$		$x = 0.05$	
	Model B	Model C	Model B	Model C
Cation $4a$				
SOF(Ag)	0.9832(5)	0.9750(4)	0.9588(4)	0.9500(2)
SOF(Zn)	0.0277(4)	0.0244(5)	0.0316(8)	0.0593 (4)
SOF(In)	0	0.0081(3)	0	0.0002(2)
100Uiso [\AA^2]	2.0040(10)	1.9880(7)	2.1130(10)	1.8770(7)
Cation $4b$				
SOF(In)	0.9750(3)	0.9814(5)	0.9500(2)	0.9498(4)
SOF(Zn)	0.0233(7)	0.0256(4)	0.0684(3)	0.0407(2)
SOF(Ag)	0.0008(1)	0	0.0088(4)	0
100Uiso [\AA^2]	2.2380(9)	2.1860(7)	2.2740(7)	2.2370(6)
Anion $8d$				
SOF(Se)	0.9729(2)	0.9814(5)	0.9474(4)	0.9825(1)
100Uiso [\AA^2]	1.6270(9)	1.5740(9)	1.562(3)	1.588(3)
x_{Se}	0.2398(3)	0.2385(3)	0.2391(2)	0.2393(2)
Reliability factors				
χ^2	1.8210	1.8250	1.5870	1.5790
wR _p	0.0975	0.0976	0.0886	0.0884
R _p	0.0778	0.0778	0.0705	0.0703

Supplementary Table 4 Structural parameters and refinement details for In–poor and Ag–poor compounds ($x=0.05$) obtained by Rietveld refinements

Parameters	In–poor		Ag–poor	
	Model B	Model C	Model B	Model C
Cation 4 <i>a</i>				
SOF(Ag)	0.9945(7)	1.0000(4)	0.9422(5)	0.9500(2)
SOF(Zn)	0.0002(6)	0.0009(3)	0.0578(6)	0.0566(7)
SOF(In)	0	0.0058(2)	0	0.0003(4)
100Uiso [Å ²]	1.9450(6)	1.9700(5)	2.1070(4)	2.0590(6)
Cation 4 <i>b</i>				
SOF(In)	0.9500(4)	0.9403(6)	1.0000	0.9997(1)
SOF(Zn)	0.0498(6)	0.0442(8)	0	-0.0066(3)
SOF(Ag)	0.0005(2)	0	0	0
100Uiso [Å ²]	2.2550(6)	2.3730(6)	2.3260(8)	2.3670(6)
Anion 8 <i>d</i>				
SOF(Se)	0.9670(5)	0.9941(3)	0.9645(3)	0.9843(3)
100Uiso [Å ²]	1.3680(3)	1.3730(6)	1.2960(8)	1.5760(7)
x_{Se}	0.2438(3)	0.2465(2)	0.2380(3)	0.2394(2)
Reliability factors				
χ^2	1.7080	1.6870	1.6870	1.6840
wR _p	0.0976	0.0970	0.0929	0.0928
R _p	0.0761	0.0760	0.0736	0.0736